



MG-1000 Maintenance Free!

MG-1000 has performed high durability and maintenance free from 1st sold to now. It has a robust and elaborate driving system to get high performance.

Feature

Easy Operation

- No set up
- Maintenance free (except lamp)
- No keys to control
- · User-friendly operation and analysis softwares provided

Fast Measurement

• 5 sec for full spectra of del, psi

Specification

- Wavelength
- 350 \sim 840 nm or 1.5 \sim 3.5 eV (UV option : 250 \sim 840 nm or 1.5 \sim 5.0 eV) Measurement items Film thickness, n, k
- Accuracy1
- Thickness range
- Throughput₂
- Angle of Incidence
- Sample size $5\text{mm} \text{ x} 5\text{mm} \sim 200 \text{ mm} \text{ x} 200 \text{ mm}$
- 400 mm (W) x 300 mm (D) x 300 mm (H) • Foot print
- Weight 15 kg (typical)

Foot note

1. Thickness measurement on specular sample Accuracy is the precision, where a static sample is repeatedly measured at the same spot and is described as three times of standard deviation.

1048.85 Å \pm 0.29 Å for 1049 Å SiO2 on c-Si

 $45 \sim 90$ with 5 step (manually variable of incidence)

 $5 \sim 10$ sec per point (depends on sample)

 $l\text{\AA} \sim 3um$ (depends on sample)

2. Throughput is the time of 1 point static sample measurement.

SE MG-1000

MG-1000 Accuracy High!

- MG-1000 is an accurate and versatile ellipsometer for characterization of all types of materials:
- dielectrics, semiconductors, polymer, organics, multi-layers and more.
- It combines high accuracy and precision with wide spectral ranges to meet any needs.
- Variable wavelength and angle of incidence allow flexible measurement capabilities.
- Also, It offers many upgraded options: automated transportation,



SE MG-1000



Application for Semiconductor





Application for OLED

